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PATENT

2877
TFW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Michael Weber-Grabau et al.

Application No.: 09/927,103

Filed: August 10, 2001

For: OPTICAL CRITICAL DIMENSION
METROLOGY SYSTEM
INTEGRATED INTO
SEMICONDUCTOR WAFER
PROCESS TOOL

Confirmation No.: 3815

Group No.: 2877

Examiner: Richard A. Rosenberger

**SUBMISSION OF REVOCATION OF
PRIOR POWERS AND APPOINTMENT
OF NEW COUNSEL BY ASSIGNEE**

353 Sacramento Street, Suite 2200
San Francisco, CA 94111
(415) 772-4900

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited
with the United States Postal Service as First Class Mail in an
envelope, addressed to: Commissioner for Patents, P.O.
Box 1450, Alexandria, VA 22313-1450 on February 28, 2006.
STALLMAN & POLLOCK LLP

Dated: 02/28 /2006

By:

Georgia K. Stith
Georgia K. Stith

Sir:

Enclosed for filing please find a duly executed Revocation of Prior Powers and
Appointment of New Counsel by Assignee for the above-identified application which specifies
an Assignment recordal date of October 7, 2005, at Reel 16851, Frame 953, and shows
Assignee's entire right, title and interest to establish ownership.

Respectfully submitted,

STALLMAN & POLLOCK LLP

Date: February 27, 2006

By:

Michael A. Stallman (Reg. No. 29,444)

Attorneys for Applicant(s)